## Notice of References Cited Application/Control No. | Applicant(s)/Patent Under Reexamination SU ET AL. | Examiner | Art Unit | Page 1 of 1

## **U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-6,031,329	02-2000	Nagano, Shinichiro	313/582
	В	US-			
	С	US-			
	D	US-			
	Е	US-			
	F	US-			
	G	US-			
	Н	US-			
	1	US-			
	J	US-			
	К	US-			
	L	US-			
	М	US-			

## **FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
*	N	CN 1269570 A	10-2000	China	BYOUNG et al.	G09F 09/313
*	0	JP 11297214 A	10-1999	Japan	AMAMIYA et al.	H01J 11/02
*	Р	JP 2000123750 A	04-2000	Japan	PARK et al.	H01J 11/02
	Q					
	R					
	s					
	Т					

## **NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	υ	
	٧	
	w	
	х	

<sup>\*</sup>A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.